

# FDS8812NZ

## N-Channel PowerTrench® MOSFET 30V, 20A, 4.0mΩ

### Features

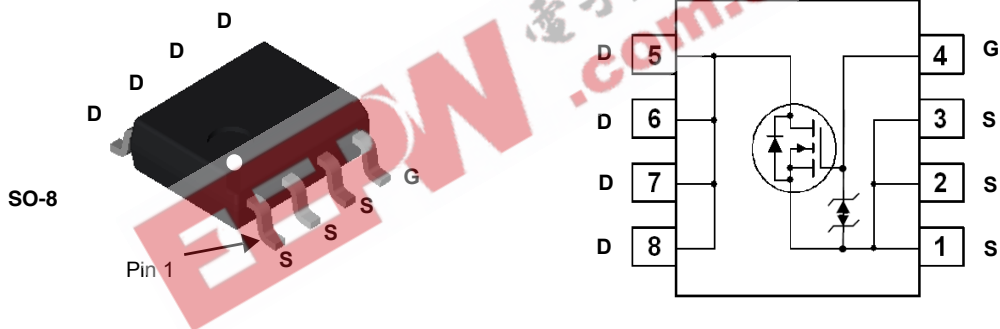
- Max  $r_{DS(on)}$  = 4.0mΩ at  $V_{GS} = 10V$ ,  $I_D = 20A$
- Max  $r_{DS(on)}$  = 4.9mΩ at  $V_{GS} = 4.5V$ ,  $I_D = 18A$
- HBM ESD protection level of 6.4kV typical (note 3)
- High performance trench technology for extremely low  $r_{DS(on)}$
- High power and current handling capability
- RoHS compliant



### General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



### MOSFET Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

| Symbol         | Parameter  | Rated Value | Units |
|----------------|--|-------------|-------|
| $V_{DS}$       | Drain to Source Voltage                          | 30          | V     |
| $V_{GS}$       | Gate to Source Voltage                           | ±20         | V     |
| $I_D$          | Drain Current -Continuous (Note 1a)              | 20          | A     |
|                | -Pulsed  | 80          |       |
| $E_{AS}$       | Single Pulse Avalanche Energy (Note 4)           | 661         | mJ    |
| $P_D$          | Power Dissipation (Note 1a)                      | 2.5         | W     |
|                | Power Dissipation (Note 1b)                      | 1.0         |       |
| $T_J, T_{STG}$ | Operating and Storage Junction Temperature Range | -55 to +150 | °C    |

### Thermal Characteristics

|                 |   |     |      |
|-----------------|---|-----|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case (Note 1)     | 25  | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1a) | 50  |      |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (Note 1b) | 125 |      |

### Package Marking and Ordering Information

| Device Marking | Device    | Reel Size | Tape Width | Quantity   |
|----------------|-----------|-----------|------------|------------|
| FDS8812NZ      | FDS8812NZ | 13"       | 12mm       | 2500 units |

### Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------|-----------|-----------------|-----|-----|-----|-------|
|--------|-----------|-----------------|-----|-----|-----|-------|

#### Off Characteristics

|                                      |   |   |    |    |          |                      |
|--------------------------------------|---|---|----|----|----------|----------------------|
| $BV_{DSS}$                           | Drain to Source Breakdown Voltage         | $I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$                | 30 |    |          | V                    |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$ |    | 19 |          | mV/ $^\circ\text{C}$ |
| $I_{DSS}$                            | Zero Gate Voltage Drain Current           | $V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$                 |    |    | 1        | $\mu\text{A}$        |
| $I_{GSS}$                            | Gate to Source Leakage Current            | $V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$             |    |    | $\pm 10$ | $\mu\text{A}$        |

#### On Characteristics (Note 2)

|  |  |  |   |     |     |                      |
|--|--|--|---|-----|-----|----------------------|
| $V_{GS(th)}$                           | Gate to Source Threshold Voltage                         | $V_{GS} = V_{DS}, I_D = 250\mu\text{A}$                          | 1 | 1.8 | 3   | V                    |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | $I_D = 250\mu\text{A}$ , referenced to $25^\circ\text{C}$        |   | -7  |     | mV/ $^\circ\text{C}$ |
| $r_{DS(on)}$                           | Static Drain to Source On Resistance                     | $V_{GS} = 10\text{V}, I_D = 20\text{A}$                          |   | 3.1 | 4.0 | m $\Omega$           |
|  |  | $V_{GS} = 4.5\text{V}, I_D = 18\text{A}$                         |   | 3.8 | 4.9 |                      |
|  |  | $V_{GS} = 10\text{V}, I_D = 20\text{A}, T_J = 125^\circ\text{C}$ |   | 4.2 | 5.3 |                      |
| $g_{FS}$                               | Forward Transconductance                                 | $V_{DS} = 5\text{V}, I_D = 20\text{A}$                           |   | 87  |     | S                    |

#### Dynamic Characteristics

|           |                              |  |      |      |          |
|-----------|------------------------------|--|------|------|----------|
| $C_{iss}$ | Input Capacitance            | $V_{DS} = 15\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$ | 5205 | 6925 | pF       |
| $C_{oss}$ | Output Capacitance           |  | 945  | 1260 | pF       |
| $C_{rss}$ | Reverse Transfer Capacitance |  | 580  | 870  | pF       |
| $R_g$     | Gate Resistance              |  | 1.5  |      | $\Omega$ |

#### Switching Characteristics

|              |                               |   |                                     |    |     |
|--------------|-------------------------------|---|-------------------------------------|----|-----|
| $t_{d(on)}$  | Turn-On Delay Time            | $V_{DD} = 15\text{V}, I_D = 20\text{A}, V_{GS} = 10\text{V}, R_{GEN} = 6\Omega$ | 18                                  | 33 | ns  |
| $t_r$        | Rise Time                     |   | 13                                  | 24 | ns  |
| $t_{d(off)}$ | Turn-Off Delay Time           |   | 55                                  | 88 | ns  |
| $t_f$        | Fall Time                     |   | 12                                  | 22 | ns  |
| $Q_g$        | Total Gate Charge             |   | $V_{GS} = 0\text{V to } 10\text{V}$ | 90 | 126 |
| $Q_g$        | Total Gate Charge             | $V_{GS} = 0\text{V to } 5\text{V}$  | 49                                  | 69 | nC  |
| $Q_{gs}$     | Gate to Source Charge         | $V_{DD} = 15\text{V}, I_D = 20\text{A}$   | 16                                  |    | nC  |
| $Q_{gd}$     | Gate to Drain "Miller" Charge |   | 18                                  |    | nC  |

#### Drain-Source Diode Characteristics

|          |                                       |   |     |     |    |
|----------|---------------------------------------|---|-----|-----|----|
| $V_{SD}$ | Source to Drain Diode Forward Voltage | $V_{GS} = 0\text{V}, I_S = 2.1\text{A}$ (Note 2)    | 0.7 | 1.2 | V  |
| $t_{rr}$ | Reverse Recovery Time                 | $I_F = 20\text{A}, di/dt = 100\text{A}/\mu\text{s}$ | 36  | 54  | ns |
| $Q_{rr}$ | Reverse Recovery Charge               |   | 33  | 50  | nC |

#### Notes:

- $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.



a)  $50^\circ\text{C/W}$  when mounted on a  $1\text{in}^2$  pad of 2 oz copper.



b)  $125^\circ\text{C/W}$  when mounted on a minimum pad.

- Pulse Test: Pulse Width < 300  $\mu\text{s}$ , Duty Cycle < 2%.
- The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
- Starting  $T_J = 25^\circ\text{C}$ ,  $L = 3\text{mH}$ ,  $I_{AS} = 21\text{A}$ ,  $V_{DD} = 30\text{V}$ ,  $V_{GS} = 10\text{V}$ .

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted

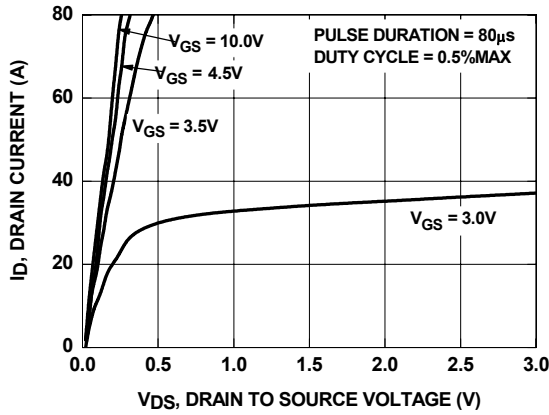


Figure 1. On-Region Characteristics

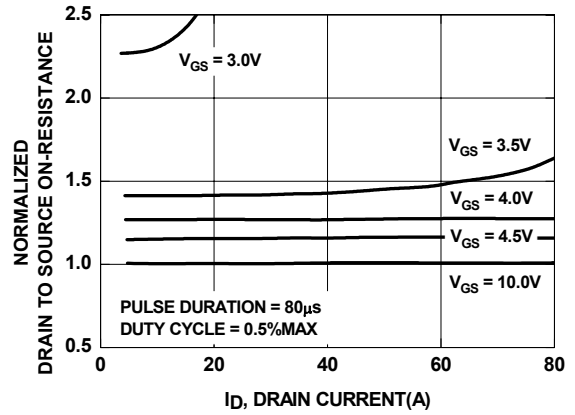


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

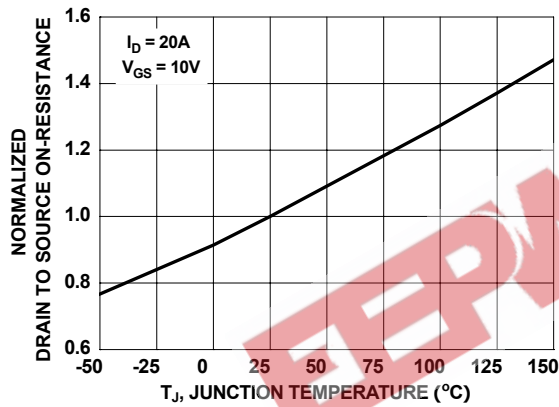


Figure 3. Normalized On-Resistance vs Junction Temperature

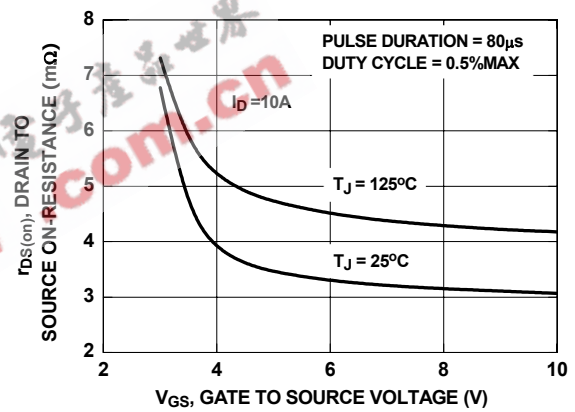


Figure 4. On-Resistance vs Gate to Source Voltage

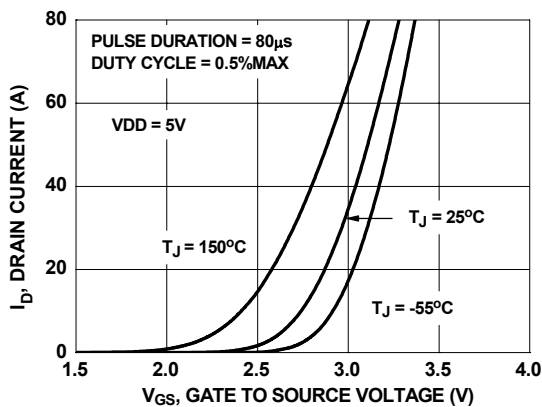


Figure 5. Transfer Characteristics

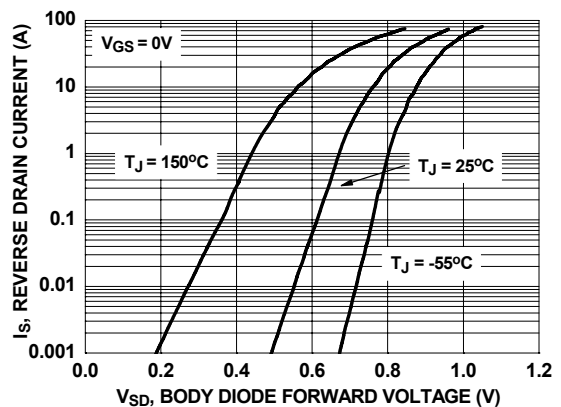
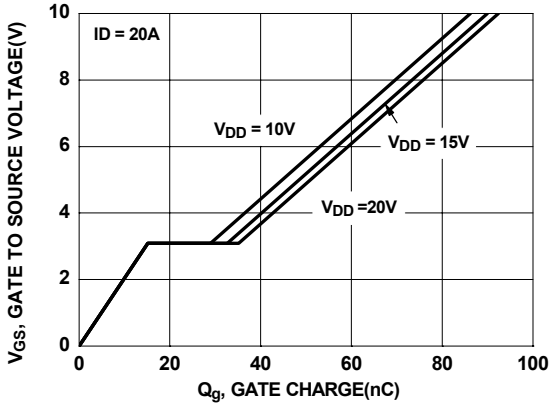
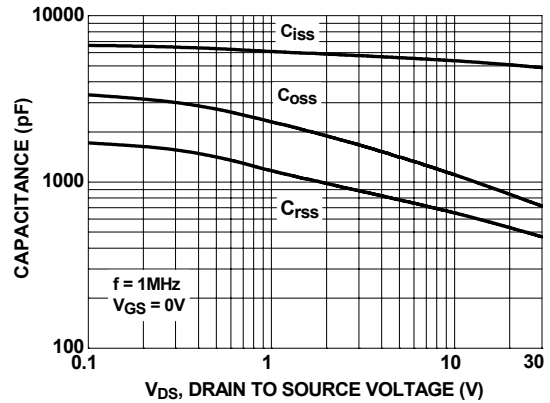


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

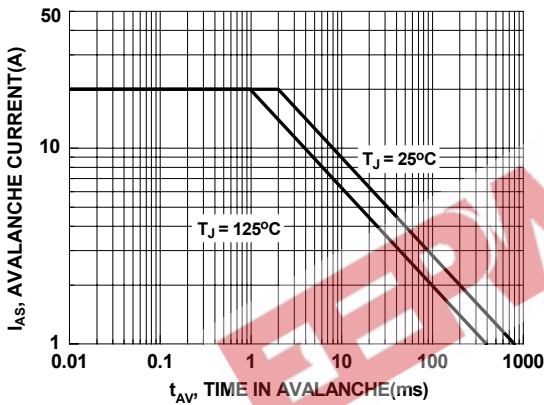
**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted



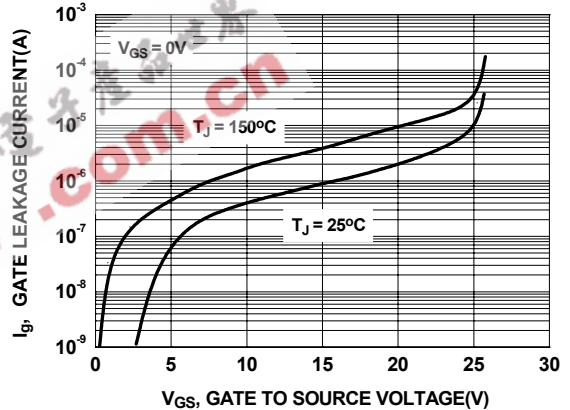
**Figure 7. Gate Charge Characteristics**



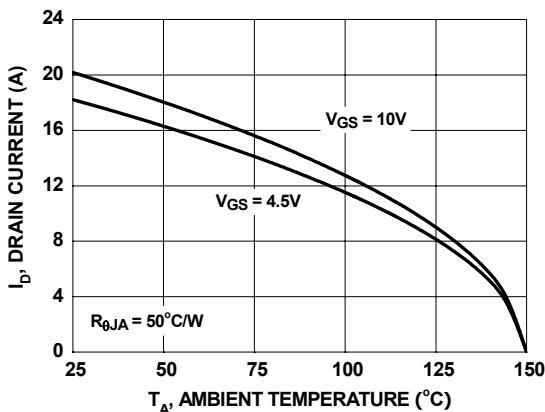
**Figure 8. Capacitance vs Drain to Source Voltage**



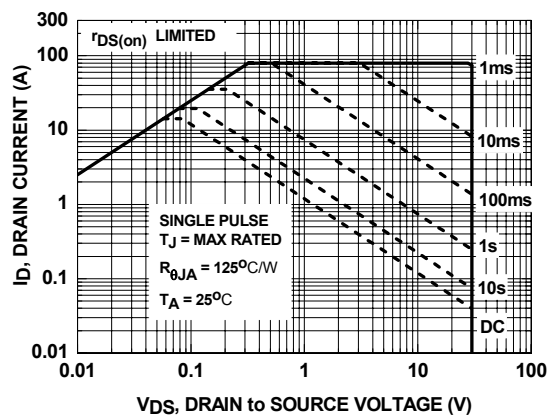
**Figure 9. Unclamped Inductive Switching Capability**



**Figure 10. Gate Leakage Current vs Gate to Source Voltage**

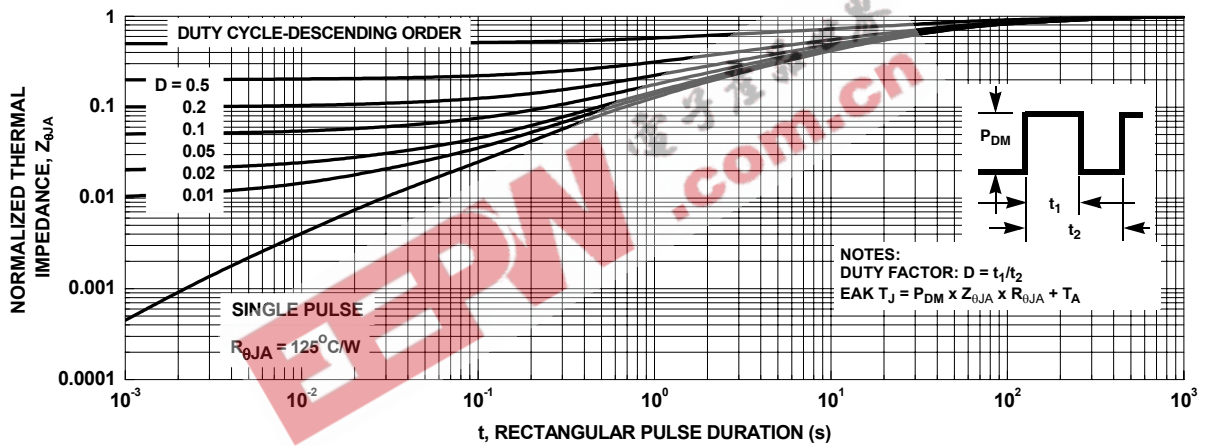
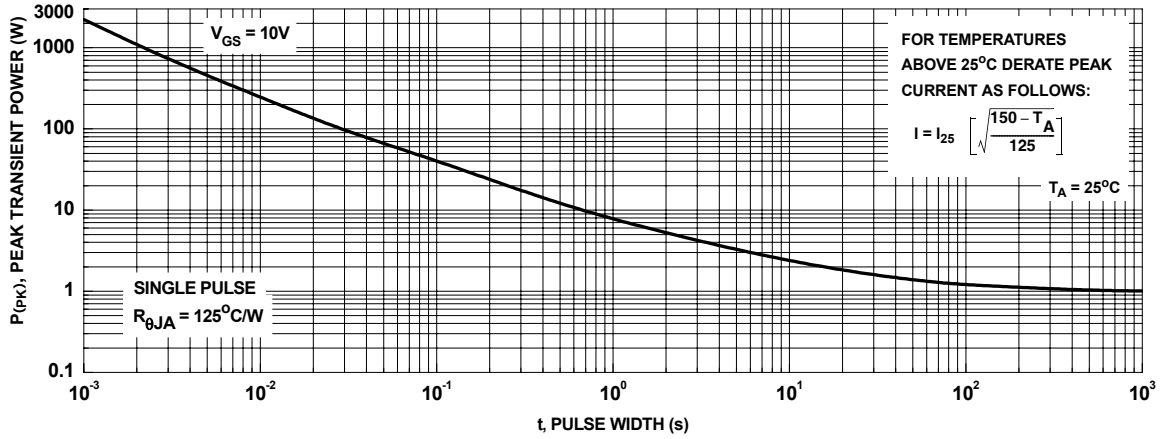


**Figure 11. Maximum Continuous Drain Current vs Ambient Temperature**



**Figure 12. Forward Bias Safe Operating Area**

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted





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